

Report of the Second Atomic Force Microscope Instruction

- Date and Time : Tuesday, 10 December, 2019
(Morning) 9:00-12:00
(Afternoon) 13:00-16:00
- Location : Center for Advanced Materials Research and
International Collaboration
- Instructor : Assoc. Prof. Lee Seungwon
- Contents : Method of using Atomic Force Microscope
 - Introduction of AFM
 - Method of using the programmes
 - Method of using AFM
 - Method of setting samples
 - Observing samples
 - Changing samples
 - Analysis method
- Participants : (Morning) 3 people
(Afternoon) 3 people
- Regarding this training :

The participants had this training for the second time and the actual measurements were made using the samples the participants brought, they seemed to be interested in the kind of data they could obtain from their own samples.

